

**Notice of References Cited**

Application/Control No.

10/593,809

Applicant(s)/Patent Under  
Reexamination  
NARAYAN ET AL.

Examiner

JONATHAN LANGMAN

Art Unit

1784

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,955,835	10-2005	Fartash, Arjang	427/250
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	S					
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Tsukimoto et al., "Microstructure of Amorphous Tantalum Nitride thin films", Thin Solid Films, Vol. 460, 2004, pgs 222-226.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.